

Search Notes**Application/Control No.**

10/659,568

Examiner

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Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	512	2/15/2006	AR
715	512	8/2/2006	AR
715	512	10/20/2006	AR
715	512	3/23/2007	AR

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) --See Search History Printout; updated 8/2/06; 10/20/06; 3/23/07	2/15/2006	AR
ACM Digital Library search - see search printouts	2/15/2006	AR
IEEE Xplore database search	2/15/2006	AR

INTERFERENCE SEARCHED

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